Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/721,170	SANCHEZ ET AL.
Examiner	Art Unit
Sanh D. Phu	2618

SEARCHED						
Class	Subclass	Date	Examiner			
455	436	7/3/06	zh.			
	423					
	423 438 449					
	449	J	J.			

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
ENST	7/3/06	22		
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